

Source of uncertainty	Ratios	Uncertainty vs. m_{jj}
<i>Theoretical uncertainties</i>		
Ren. scale V+jets (VBF)	$f_i^{W/Z,VBF}$	7.5%
Ren. scale V+jets (strong)	$f_i^{W/Z,strong}$	8.2%
Fac. scale V+jets (VBF)	$f_i^{W/Z,VBF}$	1.5%
Fac. scale V+jets (strong)	$f_i^{W/Z,strong}$	1.3%
PDF V+jets (VBF)	$f_i^{W/Z,VBF}$	0%
PDF V+jets (strong)	$f_i^{W/Z,strong}$	0%
NLO EW corr. V+jets (strong)	$f_i^{W/Z,strong}$	0.5%
Ren. scale γ +jets (VBF)	$f_i^{\gamma/Z,VBF}$	6–10%
Ren. scale γ +jets (strong)	$f_i^{\gamma/Z,strong}$	6–10%
Fac. scale γ +jets (VBF)	$f_i^{\gamma/Z,VBF}$	2.5%
Fac. scale γ +jets (strong)	$f_i^{\gamma/Z,strong}$	2.5%
PDF γ +jets (VBF)	$f_i^{\gamma/Z,VBF}$	2.5%
PDF γ +jets (strong)	$f_i^{\gamma/Z,strong}$	2.5%
NLO EW corr. γ +jets	$f_i^{\gamma/Z,strong}$	3%
<i>Experimental uncertainties</i>		
Electron reco. eff.	$R_i^{CR,proc}$, CR=Z(ee) or W(ev)	$\approx 0.5\%$ (per lepton)
Electron id. eff.	$R_i^{CR,proc}$, CR=Z(ee) or W(ev)	$\approx 1\%$ (per lepton)
Muon id. eff.	$R_i^{CR,proc}$, CR=Z($\mu\mu$) or W($\mu\nu$)	$\approx 0.5\%$ (per lepton)
Muon iso. eff.	$R_i^{CR,proc}$, CR=Z($\mu\mu$) or W($\mu\nu$)	$\approx 0.1\%$ (per lepton)
Photon id. eff.	$f_i^{\gamma/Z,proc}$	5%
Electron veto (reco)	$f_i^{W/Z,proc}$, $R_i^{CR,proc}$, CR=W($\ell\nu$)	≈ 1.5 (1)% for VBF (strong)
Electron veto (id)	$f_i^{W/Z,proc}$, $R_i^{CR,proc}$, CR=W($\ell\nu$)	≈ 2.5 (2)% for VBF (strong)
Muon veto	$f_i^{W/Z,proc}$, $R_i^{CR,proc}$, CR=W($\ell\nu$)	$\approx 0.5\%$
τ_h veto	$f_i^{W/Z,proc}$, $R_i^{CR,proc}$, CR=W($\ell\nu$)	$\approx 1\%$
Electron trigger	$R_i^{CR,proc}$, CR=Z(ee) or W(ev)	$\approx 1\%$
p_T^{miss} trigger	$R_i^{CR,proc}$, CR=Z($\mu\mu$) or W($\mu\nu$)	$\approx 2\%$
Photon trigger	$f_i^{\gamma/Z,proc}$	1%
	$f_i^{W/Z,proc}$	1–2%
JES	$R_i^{CR,proc}$, CR=W(ev) or W($\mu\nu$)	1.0–1.5%
	$R_i^{CR,proc}$, CR=Z(ee) or Z($\mu\mu$)	1%
	$f_i^{\gamma/Z,proc}$	3%
	$f_i^{W/Z,proc}$	1.0–2.5%
JER	$R_i^{CR,proc}$, CR=W(ev) or W($\mu\nu$)	1.0–1.5%
	$R_i^{CR,proc}$, CR=Z(ee) or Z($\mu\mu$)	1%
	$f_i^{\gamma/Z,proc}$	1–4%